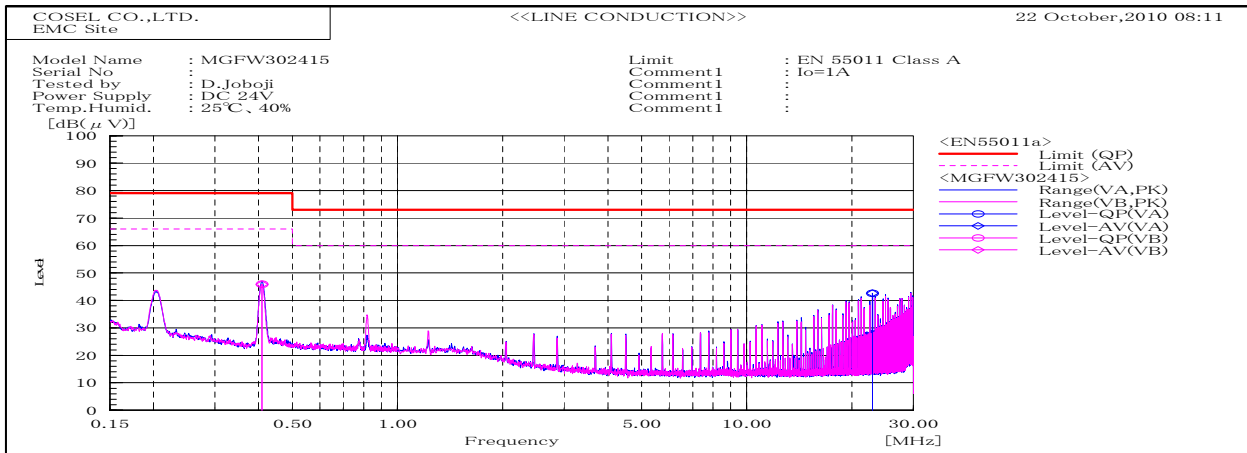
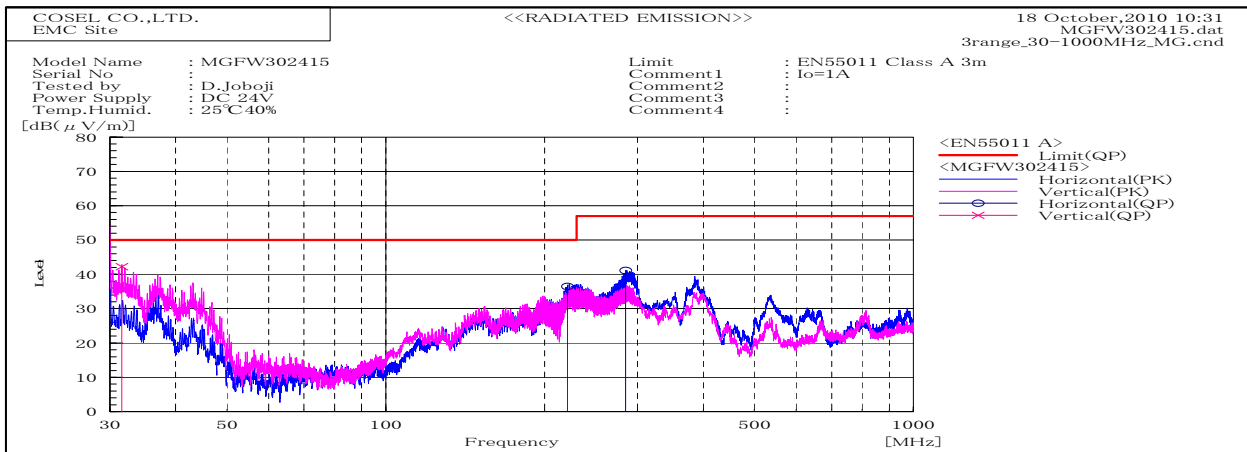


DATA SHEET		Date	22-Oct-10
Model	MGFW302415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.40939		VB	35.9	35.9	10	45.9	45.9	79	66	33.1	20.1	Pass	
22.91515		VA	31.8	31.8	10.8	42.6	42.6	73	60	30.4	17.4	Pass	

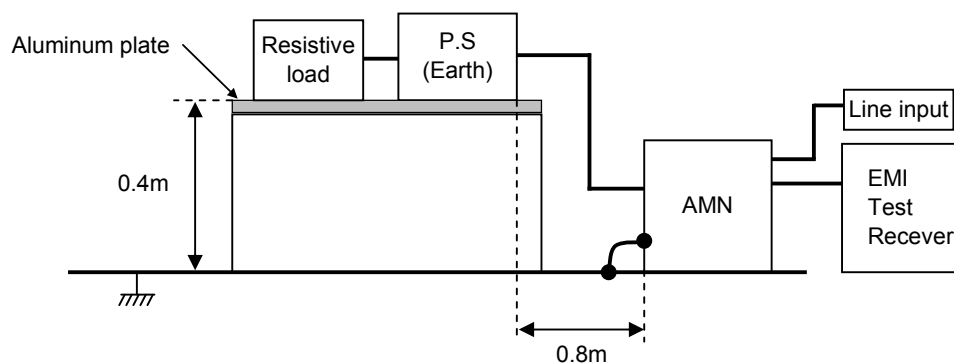


Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
31.618	V	Stable	56.5	-14.3		42.2		50	7.8	103	311	
220.955	H	Stable	57.1	-20.6		36.5		50	13.5	158	192	
285.011	H	Stable	59	-17.9		41.1		57	15.9	102	169	

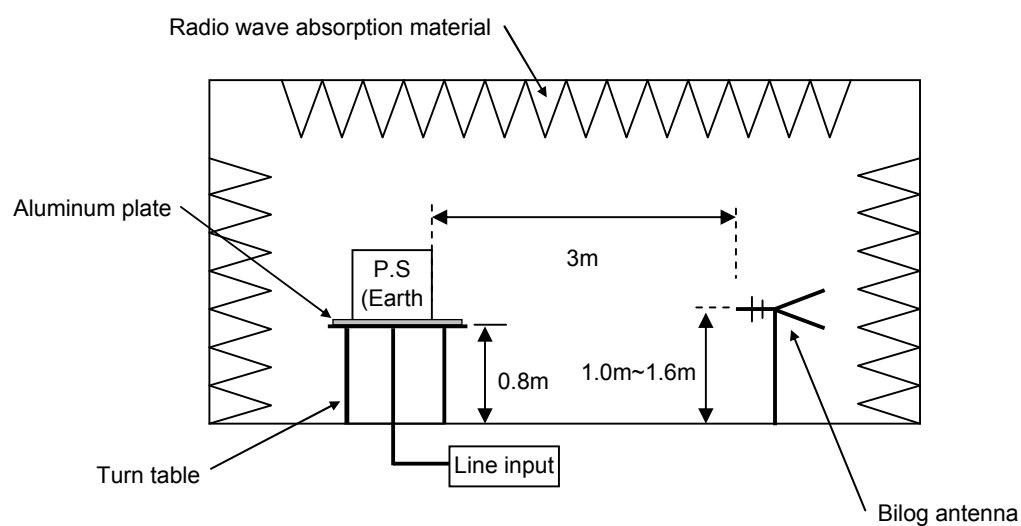
DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

1. Line conduction



2. Radiated emission

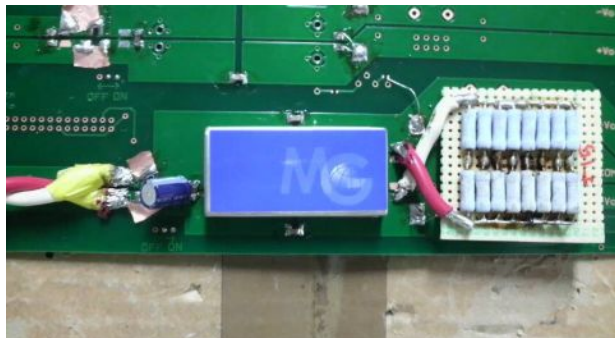


Conditions

Test : EMI
Model Name : MGFS3024□□/MGFW3024□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

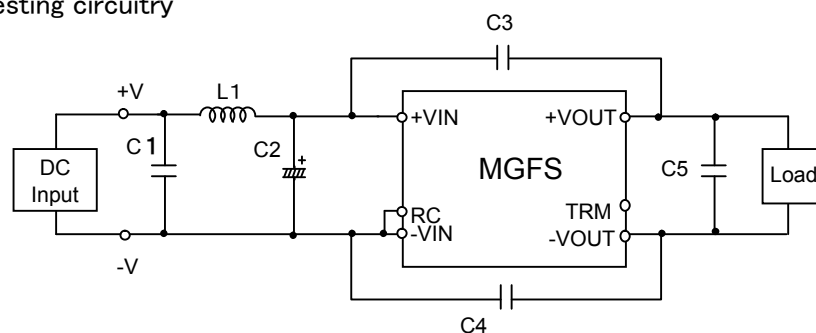


Fig.1 Testing circuitry 1

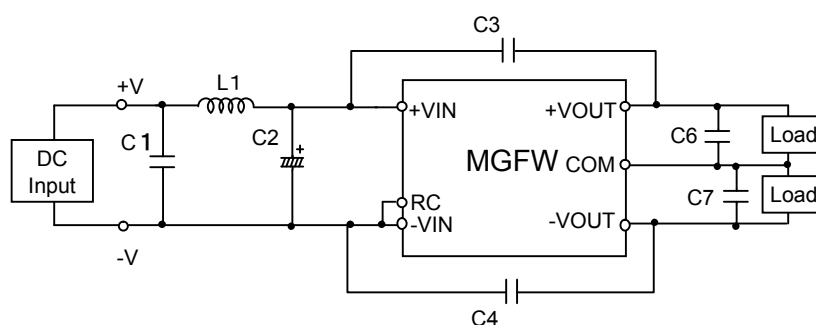


Fig.2 Testing circuitry 2

L1	: 0.6uH	CI8C-0R6	(KORIN ELECTRONICS)
C1	: 50V 4.7 μ F	Ceramic Capacitor	
C2	: 50V 100 μ F	Electrolytic Capacitor	
C3,C4	: 2kV 1000pF	Ceramic Capacitor	
C5,C6,C7	: 25V 22 μ F	Ceramic Capacitor	